PRODUCT TECHNICAL BRIEF

Oxford Instruments Xplore 30 EDS System

Oxford Instruments Xplore 30 EDS System - LeakLab solutions for leak testing, vacuum systems and test equipment.

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Technical Data

PARAMETER	PUBLISHED VALUE / INFORMATION
Active area	30 mm^2
Guaranteed Mn Kα resolution	<129 eV at 100,000 cps
Mapping count rate	>1,000,000 cps
Quantitative analysis rate	>100,000 cps
Detection range stated by Oxford Instruments	Beryllium to californium for the 30 mm^2 version
Typical functions	Point identification, spectra, quantitative analysis, maps and line scans, software-package dependent

Technical and Project Information

Compact 30 mm^2 silicon-drift EDS detector for routine SEM microanalysis. Oxford Instruments specifies Mn Kα resolution below 129 eV at 100 kcps, mapping above 1,000,000 cps and Be-to-Cf detection for the 30 mm^2 version.

Xplore 30 is a compact silicon-drift detector for routine energy-dispersive X-ray spectroscopy in a compatible scanning electron microscope. It can be supplied with AZtecOne or AZtecLive software depending on the required workflow.

Actual low-energy performance depends on window, geometry, specimen, beam conditions and calibration. Confirm SEM compatibility, port geometry, working distance, take-off angle, electronics, software tier, computer, installation and standards before ordering.

- Helium Reference Leaks
- Scanning Electron Microscopes
- Leak-Detector Accessories

WORLDWIDE PROJECT CONTACT

Send the test object or system, operating conditions, target sensitivity or pressure range, applicable standard, destination country, quantity and schedule. LeakLab will review the project scope.

mail@leaklab.org

Regarding: Oxford Instruments Xplore 30 EDS System

Specifications, standards, verification scope, availability and commercial terms must be confirmed for the exact configuration and destination jurisdiction before order or project acceptance.